PATENT S/N 09/834,751

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Sergey A. Velichko et al. Applicant:

Examiner: Craig Steven Miller

Serial No.:

09/834,751

Group Art Unit: 2857

Filed:

April 13, 2001

Docket No.: 303.750US1

CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC

TESTING

AMENDMENT AND RESPONSE UNDER 37 CFR § 1.111

MS Amendment Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

This responds to the Office Action mailed on May 12, 2004. Please amend the aboveidentified patent application as follows.